



In situ optical monitoring for the display production

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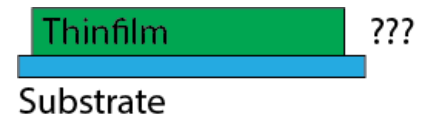
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Monitoring types

Common methods

- Time

Estimation of thickness



- Quartz Crystal

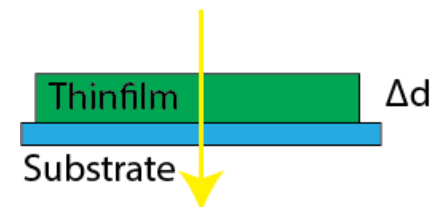
Measure mass on the resonator-not real film thickness



Optical methods

- Transmittance/Reflectance measurement

Measure optical thickness – key to understand film thickness

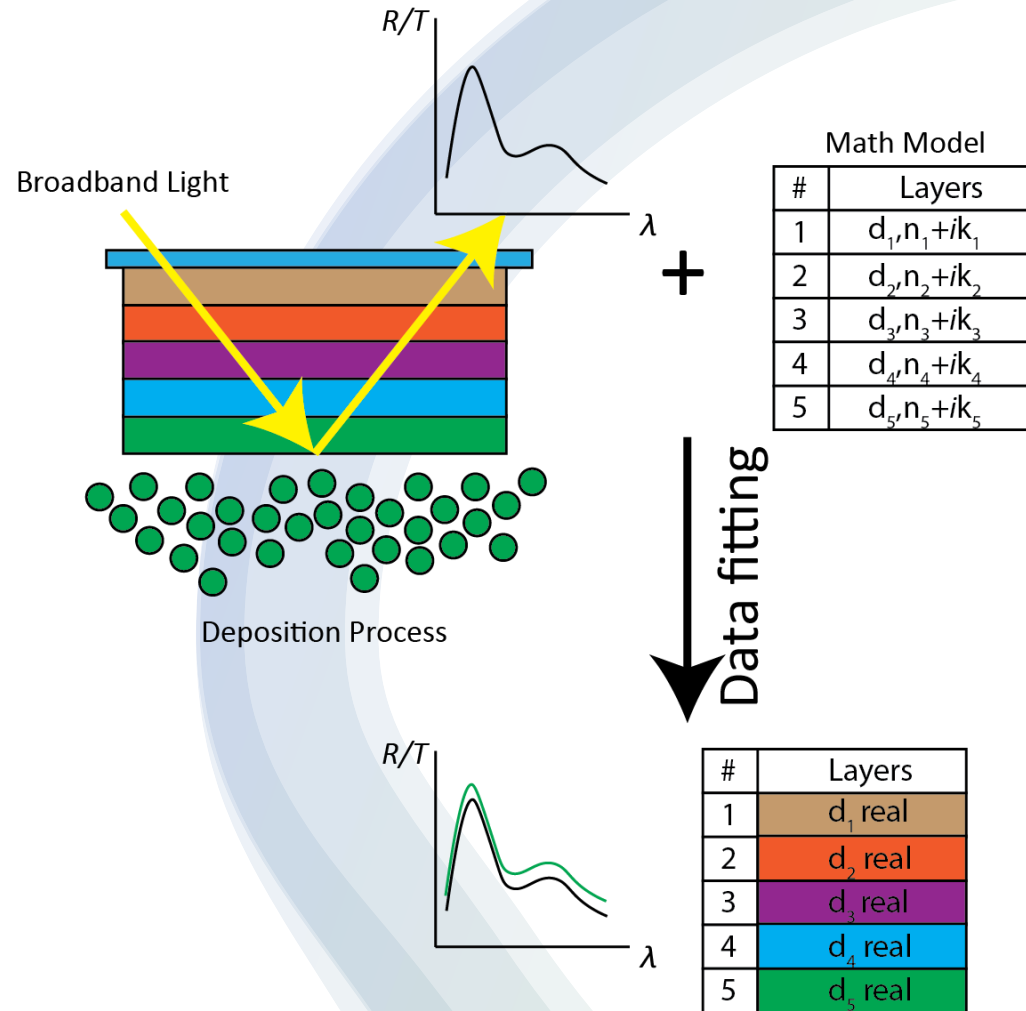


Hardware and software

- Multiple choice of monitoring strategies provides a way to enhance production yield and process tolerance
- The advanced calculation algorithm automatically defines endpoint using intensity data of an optical signal
- Smart Diagrams offer a way to visually conceptualize the control of processes. It helps easily create and understand complex behavior of feedback loops.
- All-in-one package that provides easy to use user interface and powerful functionality needed to set-up and monitor complex depositions processes.



In situ thickness re-engineering



Thank you!
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